POSITIONS AVAILABLE

MATERIALS RESEARCH LABORATORY UNIVERSITY OF ILLINOIS AT URBANA-CHAMPAIGN

RESEARCH SCIENTIST (ELECTRON MICROSCOPY)

The Center for Microanalysis of Materials in the Materials Research Laboratory of the University of Illinois at Urbana-Champaign is a major facility for the characterization of materials using electron microscopy, microchemistry and surface analysis. The Center is used by researchers in a wide range of scientific fields related to materials science. It operates and develops many instruments which are used by over 300 researchers each year. The Center has an open position for an electron microscopist, specializing in TEM.

The staff of the Center have a broad range of responsibilities. They work with users on their research, train users, maintain the instruments, and have the opportunity to develop new techniques and instrumentation.

We anticipate that the person will divide their time more or less equally between maintenance and the training and research functions. Applicants should have an advanced degree or several years of experience in an electron microscopy laboratory. They should have a good background in transmission electron microscopy and microanalysis. To handle the maintenance responsibilities, applicants should have prior experience with vacuum systems and in digital and analog electronics.

This is a non-teaching, 100% time, regular appointment with standard university benefits. Salary will be commensurate with education and experience. The position is available in the Fall of 1992. In order to ensure full consideration, applications must be received by October 31, 1992. Please send letter of application, resume and three letters of reference to Professor H. K. Birnbaum, c/o Donna Jacobs, University of Illinois, Materials Research Laboratory, 104 South Goodwin Avenue, Urbana, Illinois 61801, phone: (217)244-2944.

USED EQUIPMENT FOR SALE

- JEOL JEM-100cv/TEM, 11 year old, in good operating condition, includes: 1) specimen anticontamination trap; 2) goniometer state; 3) SEGZ-4D Zoom Stignator; 4) Haskris water recirculator. Best Offer. Call B. Soronson: (410)328-3855 (University of Maryland School of Medicine, Baltimore, Md.
- JEOL 100 TEM with Kevex EDS. Best Offer. Excellent Condition. Dr. Dan Friend: (415)476-5912 or (617)432-4875.
- Balzers 360M freeze-fracture apparatus. A classic in good working order: \$5,000. Contact Caroline Schooley, U.C. Berkeley, Tel: (510)642-2085 or Fax: (510)642-4612.
- Two complete 200KV JEOL EM's: 1) JSEM-200 TEM/STEM, with goniometer and TN2000 EDS, like new, in operation. 2) JEM-200A with TE goniometer, several years in storage, probably best used as parts for 1), packed for moving. Many additional spares: set of good H.T. diodes; another JSEM-200 mostly complete except for vacuum system; compatible parts from an early JEM-200 column and electronics (including H.T. cables and components). Michael Marko, Wadsworth Labs, Albany, NY: Tel.: (518)474-7049.
- FREE TEM: Siemens 102 (1973 vintage) used, and under service contract, through 1988 for high resolution imaging (2Å) and tilting (24° about two axes). Robert Keyes, Cornell Univ. Tel: (607)255-6421.
- KEVEX 7500 + SESAME for EDS or EDS/WDS microanalysis. 4 years old. Mounts on 5th spectrometer port of Cameca EMP. Larry Taylor, Univ. of Tennessee, Tel: (615)974-6013, Fax: (615)974-2368.

Help Would be Appreciated

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We have an interest in expanding the "usefulness" of the newsletter relating to employment - both for those seeking new employment and for those having a position to fill.

Considering the factors of readership (over 10,000 in North America with an interest in microscopy) and timeliness (a monthly publication with fast turnaround), we may have advantages not available with any other publication.

We would like to request that readers invite those in their companies/organizations that are involved in the hiring process to accept a no cost copy of the newsletter. We would be delighted to accept such no cost subscription request by mail, telephone (608/836-1970) or Fax (608/836-1969).

Our new advertising rate for "Positions" "Available", with the above format, is \$100 per column inch. For "Situations Wanted", it is a flat \$75 which will cover around 35 words.

SITUATIONS WANTED

- Experienced R&D engineer (B.A. Physics, M.Sc. Electrical Engineering) seeks challenging position. Background in FESEM, Focused Ion Beam Repair tool, Thin Film deposition using MBE (Molecular Beam Epitaxy), LPE (Liquid Phase Epitaxy) and computer programming. Jacob Fuchs (Brighton, MA): Tel.: (617)787-4134.
- Electron Microprobe Analyst with 25+ years experience with several microprobes including ARL SEMQ and JEOL 8600. Also with JEOL 2000FX TEM, Noran 2010/5502 EDS and basic XRD and XRF. Programming ability in Flextran, Fortran and Basic. Specific interest in quantitative composition mapping. Robert Heyman (Houston, TX): Tel.: (713)449-9743.

You know it's going to be a bad day when you compliment the Boss' wife on her unusual perfume and she isn't wearing any.

- - Ed.



The Microbeam Analysis Society (MAS) is a non-profit organization of professionals who have an active interest in microbeam instrumentation. The Society provides a forum for members from industrial, government and academic settings to exchange ideas regarding the R&D aspects of microbeam analysis, including fundamental principles, instrumentation development and applications.

The Society sponsors or co-sponsors an annual meeting, including invited and contributed presentations and a commercial exhibit, highlighting the latest advances in the field of microbeam analysis. Papers are published in the annual proceedings volume.

Members are recognized annually for outstanding scientific contributions, funded by corporate sponsors. Honorary and emeritus memberships, as well as distinguished service awards, are given to recognize outstanding contributions to the field and the Society.

The Society has formal affiliations with local scientific groups interested in microbeam analysis and sponsors a tour speakers program that brings distinguished scientists to local meetings.

The Society maintains a library of computer programs, databases, and AV material related to microanalysis applications. Contributions to the library are received from members. Members may use the library for a nominal handling fee.

For additional information concerning the Society, contact:

Bob Warner Art Chotos

MAS Membership Chairman MAS Membership Services

General Electric Valecitos Nuclear Ctr Tel.: (818)357-0183

Tel.: (510)862-4389

Microbeam Analysis, a peer-reviewed scholarly journal, is the official publication of the Microbeam Analysis Society (MAS). Published by VCH Publishers, Inc., a prestigious scientific publisher. It will appear bi-monthly beginning with the Sept/Oct, 1992 issue.

Microbeam Analysis reports on new developments in techniques of microscopic analysis, with an emphasis on spectroscopy combined with microscopy and microanalysis. The journal also welcomes application-orientated papers.

Microbeam Analysis aims to create a broad interdisciplinary forum for those interested in microbeam analysis, including:

biologists

geologists

chemists

material scientists

environmental scientists

physicists

Microbeam Analysis will encompass many different microbeam analysis techniques, including:

- Analytical Electron Microscopy including X-ray Microanalysis, Electron Energy Loss Spectroscopy and Electron Diffraction.
- Optical Microanalysis including Raman Microprobe, FT/IR Microspectroscopy, Confocal and Fluorescence Imaging Microscopy.
- Microprobe Mass Spectrometry including Ion and Laser Microprobe Techniques.
- Scanned Probe Microscopies/Spectroscopies including STM, AFM, Tunneling Spectroscopy and Related Techniques.
- Computer Aided Imaging & Microbeam Analysis including Instrumentation, Data Acquisition, Data and Image Processing Techniques, Quantification of Spectral/Image Information.
- X-ray & Electron Spectroscopies including X-ray Fluorescence and Nuclear Microprobes, Auger Electron Spectroscopy and X-ray Photoelectron Spectroscopy.
- **Emerging Microanalysis Techniques** including New Advances in Microbeam Analysis Instrumentation.

MICROBEAM ANALYSIS SOCIETY - Membership Application 1993

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MICROSCOPY TODAY

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